

L Number	Hits	Search Text	DB	Time stamp
1	2	6490368.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 11:33
6	10	382/147	USPAT	2003/09/05 11:42
	2	4926452.pn.	US-PGPUB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/09/05 11:33
	2	5081656.pn.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/08/30 23:20
	2	5097492.pn.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/08/30 23:20
	2	5199054.pn.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/08/30 23:21
	2	5259012.pn.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/08/30 23:22
	2	5291535.pn.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/08/30 23:22
	2	5561696.pn.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/08/30 23:23
	2	5583904.pn.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/08/30 23:24
	2	5621811.pn.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/08/30 23:41
	2	5687209.pn.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/08/30 23:25
	118	378/22.ccls.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/08/30 23:30
	216	382/147.ccls.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2003/08/30 23:30

	324	378/21.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/30 23:31
	1287	((identify\$3 or inspect\$3 or evaluat\$3) with solder\$3 with (joint\$1 or connection\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:17
	21	((identify\$3 or inspect\$3 or evaluat\$3) with solder\$3 with (joint\$1 or connection\$1)) and ((distance or space or gap) with (mount\$3 with surface\$1 with board))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 11:42
	65	((identify\$3 or inspect\$3 or evaluat\$3) with solder\$3 with (joint\$1 or connection\$1)) and ((distance or space or gap) with (surface\$1 with board))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:07
	5	((identify\$3 or inspect\$3 or evaluat\$3) with solder\$3 with (joint\$1 or connection\$1)) and (neighbor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:08
	683	((distance or space or gap) with (mount\$3 with surface\$1 with board) same (printed with circuit))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:17
	612	((distance or space) with (mount\$3 with surface\$1 with board) same (printed with circuit))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:17
	10	((distance or space or gap) with (mount\$3 with surface\$1 with board) same (printed with circuit)) and ((defect\$1 or quality) with solder\$3 with (joint\$1 or connection\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:27
	0	((identify\$3 or inspect\$3 or evaluat\$3) with solder\$3 with (joint\$1 or connection\$1)) and (box adj plot)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:28
	73	box adj plot	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:28
	64	(box adj plot) and (analy\$4)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:28
	1	((box adj plot) and (analy\$4)) and (solder)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/08/31 00:28
	185363	(chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:18

	33687	((chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria)) and ((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:25
	3	((((chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria)) and ((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5))) and (((printed adj circuit adj board) with solder with joint\$1) same ((location or position) with solder with (joint\$1 or connection\$1)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:26
	1	((((chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria)) and ((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5))) and (((printed adj circuit adj board) with solder with joint\$1) same ((location or position) with solder with (joint\$1 or connection\$1)))) and ((distance or space) with mount\$3 with surface with board with device)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:56
	438825	((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:25
	49	(((printed adj circuit adj board) with solder with joint\$1) same ((location or position) with solder with (joint\$1 or connection\$1)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:53
	380	((distance or space) with mount\$3 with surface with board with device)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:27
	1	((((printed adj circuit adj board) with solder with joint\$1) same ((location or position) with solder with (joint\$1 or connection\$1)))) and (((distance or space) with mount\$3 with surface with board with device))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:27
	92	(((printed adj circuit adj board) with solder with joint\$1) and ((location or position) with solder with (joint\$1 or connection\$1)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 16:03
	6	(((chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria)) and ((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5))) and (((printed adj circuit adj board) with solder with joint\$1) and ((location or position) with solder with (joint\$1 or connection\$1))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:56

	1	((chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria)) and ((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5))) and (((printed adj circuit adj board) with solder with joint\$1) and ((location or position) with solder with (joint\$1 or connection\$1))))) and ((distance or space) with mount\$3 with surface with board with device)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 15:56
	1514	((location or position) with solder with (joint\$1 or connection\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 16:03
	239	((distance or space) with mount\$3 with surface with (circuit with board) with device\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 16:04
	1	((chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria)) and ((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5))) and (((location or position) with solder with (joint\$1 or connection\$1))))) and ((distance or space) with mount\$3 with surface with (circuit with board) with device\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 16:05
	5	((location or position) with solder with (joint\$1 or connection\$1))) and ((distance or space) with mount\$3 with surface with (circuit with board) with device\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/03 16:06
	21	((chang\$3 or adjust\$3 or adapt\$3 or calculat\$3 or alter\$3 or modif\$4 or set\$4) with (threshold or criteria)) and ((defect\$3 or fault\$1 or error\$1 or quality) with (inspect\$3 or check\$3 or detect\$3 or test\$3 or examin\$5))) and (((location or position) with solder with (joint\$1 or connection\$1))))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 11:53
	1	((distance adj between) with (mounting adj surface) with device with (circuit adj board) with solder with (joint\$1 or connection\$1)) and (location or position)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 15:36
	1	((distance or space) with (mounting adj surface) with device with (circuit adj board) with solder with (joint\$1 or connection\$1)) and (location or position)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 15:38
	3	((distance or space) with (moun\$3 with surface) with device with (circuit adj board) with solder with (joint\$1 or connection\$1)) and (location or position)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 15:39
	8	((distance or space or gap) with surface with device with (circuit adj board)) and (solder with (joint\$1 or connection\$1))and (location or position)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 16:17

	3	((distance or space or gap) with surface with device with (circuit adj board)) and (solder with (joint\$1 or connection\$1))and (location or position) and (threshold or criteria or range or limit)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 15:53
	1	((distance or space) with (mounting adj surface) with device with (circuit adj board) with solder with (joint\$1 OR connection\$1)) AND (location OR position)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/04 15:53
	84	((distance or space or gap) with surface with device with (circuit adj board)) and (solder with (joint\$1 or connection\$1))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 07:30
	1	RE35,423.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 07:32
	2	6,580,501.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 07:31
	2	5,780,866.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 07:31
	2	4,792,683.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 07:31
	219	702/35.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 11:26
	181	702/33.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/09/05 11:26